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	2 Mobile ion-induced data retention failure in NOR flash

2 Mobile ion-induced data retention failure in NOR flash memory cell

Lee, W.H.; Dong-Kyu Lee; Keon-Soo Kim; Kun-Ok Ahn; Kang-Deog Suh;

Device and Materials Reliability, IEEE Transactions on , Volume: 1

Issue: 2, June 2001 | Page(s): 128-132

[Abstract] [PDF Full-Text (152 KB)] IEEE JNL

3 A channel-erasing 1.8 V-only 32 Mb NOR flash EEPROM with a bit-line direct-sensing scheme

Atsumi, S.; Umezawa, A.; Tanzawa, T.; Taura, T.; Shiga, H.; Takano, Y.; Miyaba, T.; Matsui, M.; Watanabe, H.; Isobe, K.; Kitamura, S.; Yamada, S.; Saito, M.; Mori, S.; Watanabe, T.; Solid-State Circuits Conference, 2000. Digest of Technical Papers. ISSCC. 2000 IEEE International, 7-9 Feb. 2000
Page(s): 276 -277, 464-5

[Abstract] [PDF Full-Text (325 KB)] IEEE CNF

4 A flash IC card with programmable security code

Liu Kai; Pan li-yang; Zhu jun;

ASIC, 2001. Proceedings. 4th International Conference on , 23-25

Oct. 2001

Page(s): 584 -587

[Abstract] [PDF Full-Text (314 KB)] IEEE CNF

5 A channel-erasing 1.8-V-only 32-Mb NOR flash EEPROM with a bitline direct sensing scheme

Atsumi, S.; Umezawa, A.; Tanzawa, T.; Taura, T.; Shiga, H.; Takano, Y.; Miyaba, T.; Matsui, M.; Watanabe, H.; Isobe, K.; Kitamura, S.; Yamada, S.; Saito, M.; Mori, S.; Watanabe, T.;

Solid-State Circuits, IEEE Journal of , Volume: 35 Issue: 11 , [Nov.]

2000

Page(s): 1648 -1654

[Abstract] [PDF Full-Text (152 KB)] IEEE JNL

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